

Quad 2-Channel Multiplexer With 5V-Tolerant Inputs

The MC74LVX157 is an advanced high speed CMOS quad 2-channel multiplexer. The inputs tolerate voltages up to 7V, allowing the interface of 5V systems to 3V systems.

It consists of four 2-input digital multiplexers with common select (S) and enable ($\bar{E}$) inputs. When $\bar{E}$ is held High, selection of data is inhibited and all the outputs go Low.

The select decoding determines whether the I0n or I1n inputs get routed to the corresponding Zn outputs.

- High Speed: $t_{PD} = 5.1\text{ns}$ (Typ) at $V_{CC} = 3.3\text{V}$
- Low Power Dissipation: $I_{CC} = 4\mu\text{A}$ (Max) at $T_A = 25^\circ\text{C}$
- Power Down Protection Provided on Inputs
- Balanced Propagation Delays
- Low Noise: $V_{OLP} = 0.5\text{V}$ (Max)
- Pin and Function Compatible with Other Standard Logic Families
- Latchup Performance Exceeds 300mA
- ESD Performance: HBM > 2000V; Machine Model > 200V

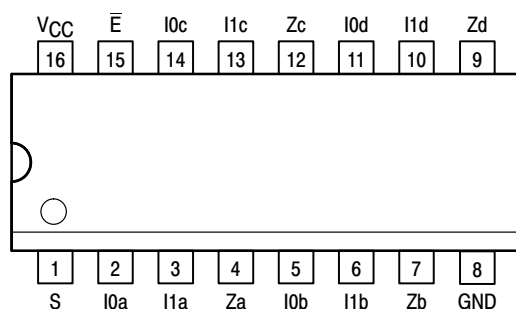


Figure 1. 16-Lead Pinout (Top View)

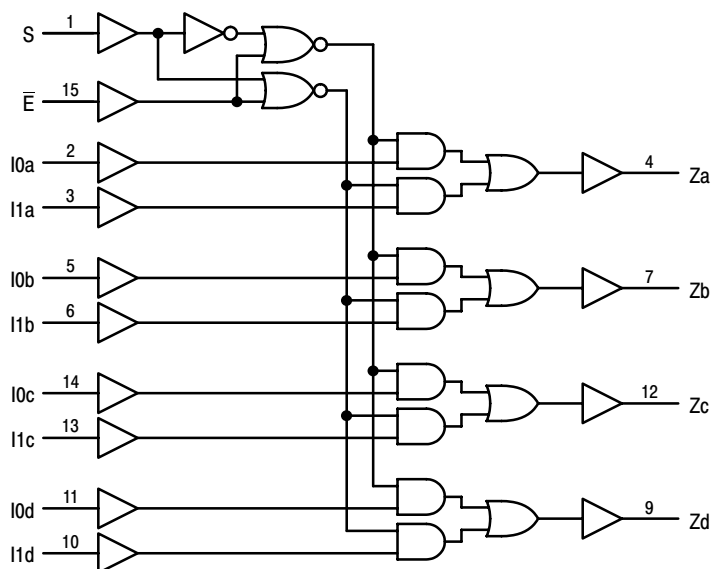
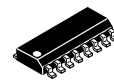


Figure 2. Logic Diagram

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D SUFFIX
16-LEAD SOIC PACKAGE
CASE 751B-05



DT SUFFIX
16-LEAD TSSOP PACKAGE
CASE 948F-01



M SUFFIX
16-LEAD SOIC EIAJ PACKAGE
CASE 966-01

PIN NAMES

Pins	Function
I0n	Source 0 Data Inputs
I1n	Source 1 Data Inputs
$\bar{E}$	Enable Input
S	Select Input
Zn	Outputs

TRUTH TABLE

INPUTS				OUTPUT
$\bar{E}$	S	I0n	I1n	Zn
H	X	X	X	L
L	H	X	L	L
L	H	X	H	H
L	L	L	X	L
L	L	H	X	H

H = High Voltage Level; L = Low Voltage Level; X = High or Low Voltage Level; For I_{CC} Reasons DO NOT FLOAT Inputs

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MAXIMUM RATINGS*

Symbol	Parameter	Value	Unit
V _{CC}	DC Supply Voltage	−0.5 to +7.0	V
V _{in}	DC Input Voltage	−0.5 to +7.0	V
V _{out}	DC Output Voltage	−0.5 to V _{CC} +0.5	V
I _{IK}	Input Diode Current	−20	mA
I _{OK}	Output Diode Current	±20	mA
I _{out}	DC Output Current, per Pin	±25	mA
I _{CC}	DC Supply Current, V _{CC} and GND Pins	±50	mA
P _D	Power Dissipation	180	mW
T _{stg}	Storage Temperature	−65 to +150	°C

* Absolute maximum continuous ratings are those values beyond which damage to the device may occur. Exposure to these conditions or conditions beyond those indicated may adversely affect device reliability. Functional operation under absolute–maximum–rated conditions is not implied.

RECOMMENDED OPERATING CONDITIONS

Symbol	Parameter	Min	Max	Unit
V _{CC}	DC Supply Voltage	2.0	3.6	V
V _{in}	DC Input Voltage	0	5.5	V
V _{out}	DC Output Voltage	0	V _{CC}	V
T _A	Operating Temperature, All Package Types	−40	+85	°C
Δt/ΔV	Input Rise and Fall Time	0	100	ns/V

DC ELECTRICAL CHARACTERISTICS

Symbol	Parameter	Test Conditions	V _{CC} V	T _A = 25°C			T _A = −40 to 85°C		Unit
				Min	Typ	Max	Min	Max	
V _{IH}	High–Level Input Voltage		2.0 3.0 3.6	1.5 2.0 2.4			1.5 2.0 2.4		V
V _{IL}	Low–Level Input Voltage		2.0 3.0 3.6			0.5 0.8 0.8		0.5 0.8 0.8	V
V _{OH}	High–Level Output Voltage (V _{in} = V _{IH} or V _{IL})	I _{OH} = −50μA I _{OH} = −50μA I _{OH} = −4mA	2.0 3.0 3.0	1.9 2.9 2.58	2.0 3.0		1.9 2.9 2.48		V
V _{OL}	Low–Level Output Voltage (V _{in} = V _{IH} or V _{IL})	I _{OL} = 50μA I _{OL} = 50μA I _{OL} = 4mA	2.0 3.0 3.0		0.0 0.0	0.1 0.1 0.36		0.1 0.1 0.44	V
I _{in}	Input Leakage Current	V _{in} = 5.5V or GND	3.6			±0.1		±1.0	μA
I _{CC}	Quiescent Supply Current	V _{in} = V _{CC} or GND	3.6			4.0		40.0	μA

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AC ELECTRICAL CHARACTERISTICS (Input $t_r = t_f = 3.0\text{ns}$)

Symbol	Parameter	Test Conditions	$T_A = 25^\circ\text{C}$			$T_A = -40 \text{ to } 85^\circ\text{C}$		Unit
			Min	Typ	Max	Min	Max	
t_{PLH} , t_{PHL}	Propagation Delay, Input to Output	$V_{CC} = 2.7\text{V}$ $C_L = 15\text{pF}$ $C_L = 50\text{pF}$		6.6 9.1	12.5 16.0	1.0 1.0	15.5 19.0	ns
		$V_{CC} = 3.3 \pm 0.3\text{V}$ $C_L = 15\text{pF}$ $C_L = 50\text{pF}$		5.1 7.6	7.9 11.4	1.0 1.0	9.5 13.0	
t_{PLH} , t_{PHL}	Propagation Delay, S to Zn	$V_{CC} = 2.7\text{V}$ $C_L = 15\text{pF}$ $C_L = 50\text{pF}$		8.9 11.4	16.9 20.4	1.0 1.0	20.5 24.0	ns
		$V_{CC} = 3.3 \pm 0.3\text{V}$ $C_L = 15\text{pF}$ $C_L = 50\text{pF}$		7.0 9.5	11.0 14.5	1.0 1.0	13.0 16.5	
t_{PLH} , t_{PHL}	Propagation Delay, $\bar{E}$ to Zn	$V_{CC} = 2.7\text{V}$ $C_L = 15\text{pF}$ $C_L = 50\text{pF}$		9.1 11.6	17.6 21.1	1.0 1.0	20.5 24.0	ns
		$V_{CC} = 3.3 \pm 0.3\text{V}$ $C_L = 15\text{pF}$ $C_L = 50\text{pF}$		7.2 9.7	11.5 15.0	1.0 1.0	13.5 17.0	
t_{OSHL} t_{OSLH}	Output-to-Output Skew (Note 1.)	$V_{CC} = 2.7\text{V}$ $C_L = 50\text{pF}$ $V_{CC} = 3.3 \pm 0.3\text{V}$ $C_L = 50\text{pF}$			1.5 1.5		1.5 1.5	ns

1. Skew is defined as the absolute value of the difference between the actual propagation delay for any two separate outputs of the same device. The specification applies to any outputs switching in the same direction, either HIGH-to-LOW (t_{OSHL}) or LOW-to-HIGH (t_{OSLH}); parameter guaranteed by design.

CAPACITIVE CHARACTERISTICS

Symbol	Parameter	$T_A = 25^\circ\text{C}$			$T_A = -40 \text{ to } 85^\circ\text{C}$		Unit
		Min	Typ	Max	Min	Max	
C_{in}	Input Capacitance		4	10		10	pF
C_{PD}	Power Dissipation Capacitance (Note 2.)		20				pF

2. C_{PD} is defined as the value of the internal equivalent capacitance which is calculated from the operating current consumption without load. Average operating current can be obtained by the equation: $I_{CC(OPR)} = C_{PD} \cdot V_{CC} \cdot f_{in} + I_{CC}/4$ (per bit). C_{PD} is used to determine the no-load dynamic power consumption; $P_D = C_{PD} \cdot V_{CC}^2 \cdot f_{in} + I_{CC} \cdot V_{CC}$.

NOISE CHARACTERISTICS (Input $t_r = t_f = 3.0\text{ns}$, $C_L = 50\text{pF}$, $V_{CC} = 3.3\text{V}$, Measured in SOIC Package)

Symbol	Characteristic	$T_A = 25^\circ\text{C}$		Unit
		Typ	Max	
V_{OLP}	Quiet Output Maximum Dynamic V_{OL}	0.3	0.5	V
V_{OLV}	Quiet Output Minimum Dynamic V_{OL}	-0.3	-0.5	V
V_{IHD}	Minimum High Level Dynamic Input Voltage		2.0	V
V_{ILD}	Maximum Low Level Dynamic Input Voltage		0.8	V

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SWITCHING WAVEFORMS

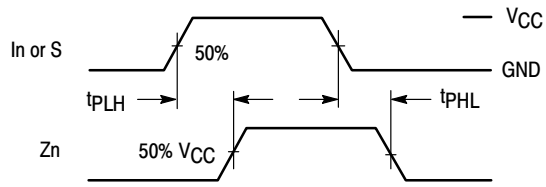


Figure 3.

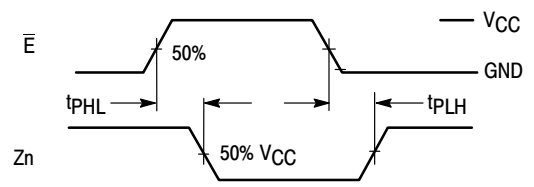
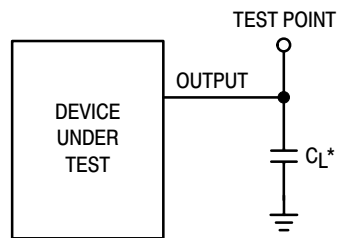


Figure 4.

TEST CIRCUIT



*Includes all probe and jig capacitance

Figure 5. Propagation Delay Test Circuit